Supplemental information

Figure S1. The temperature correction applied to the *in situ* experiments used the regression equations for above and below room temperature.



Figure S2. XRPD patterns of the ammonium sulfate 200 *hkl* near the polymorphic transition at -50.0 °C were used for correcting the *in situ* low-temperature experiments.



Figure S3. XPRD patterns of adamantane near the face-centered to primitive polymorphic transformation at -65.5 °C were used for correcting the *in situ* low-temperature experiments.



 $P\bar{4}2_1c$ a = 9.341 Å and c = 8.964 Å at -67.0 °C

Figure S4. Fraction of ccp adamantane as a function of temperature near the transformation at -65.5 °C (bold vertical line). The correction temperature (**X**) is at the 0.5 fractional amount.





Figure S5. The thermal reaction of film 1 ramped to 130 °C Ag₃O at 35 °C/min and scanned for 41 h.

Figure S6. The Ag₃O wt. % verses unit-cell volume at ambient conditions for the *ex situ* products of ball-milled jet-milled film (B1).



unit-cell volume (Å³)

Figure S7. The Ag₃O *a* axis and *c* axis at ambient conditions for the *ex situ* products of reacted jet-milled films. The data from Beesk *et al.* (1981) (grey square) were measured on a single crystal hydrothermally synthesized on Ag metal and were scaled using Mo $K\bar{a}$ from TOPAS as shown by the arrow from the grey square to the black square.



Figure S8. The refinement for film 1 sonicated in isopropyl alcohol for 45 sec using a TOPAS "structure" model for refining LT Ag₂CO₃. The peak at 32.718° overlaps the peak for Ag₂O *111*, the intensity at 32.72° and 34.15° is likely generated by stacking faults in Ag₃O and/or disordered β Ag₂CO₃, and the intensity near 44.2° is from LT Ag₂CO₃ and stacking faults in Ag.



Ag₃O ms12

Figure S9. The refinement of film 1 sonicated in cyclohexane for 3 min using a TOPAS "structure" model for refining LT Ag₂CO₃. The intensity at 32.816° is part of the Ag₂O *111*, the intensity at 34.142° is likely generated by stacking faults in Ag₃O and/or disordered β Ag₂CO₃, and the intensity near 44.2° is from stacking faults in Ag and from LT Ag₂CO₃.



Ag₃O ms12





Figure S11. SEM photomicrograph of (a) faceted Ag₃O crystals produced by a thermal reaction of a jet-milled thin film; temperature and time period unavailable, (b) the product from the *in situ* thermal reaction of film 1 after 148 °C and 39 h (III.B), and (c) *ex situ* thermal-reaction product 1e (60 °C, 1 yr).









Figure S12. Published Ag₂O a(T). The *ex situ* values at ambient *T* from Allen (1960), Faivre (1940), and Taylor *et al.* (2005) were corrected for thermal expansion and graphed at their annealing temperatures.

